

FIG.1

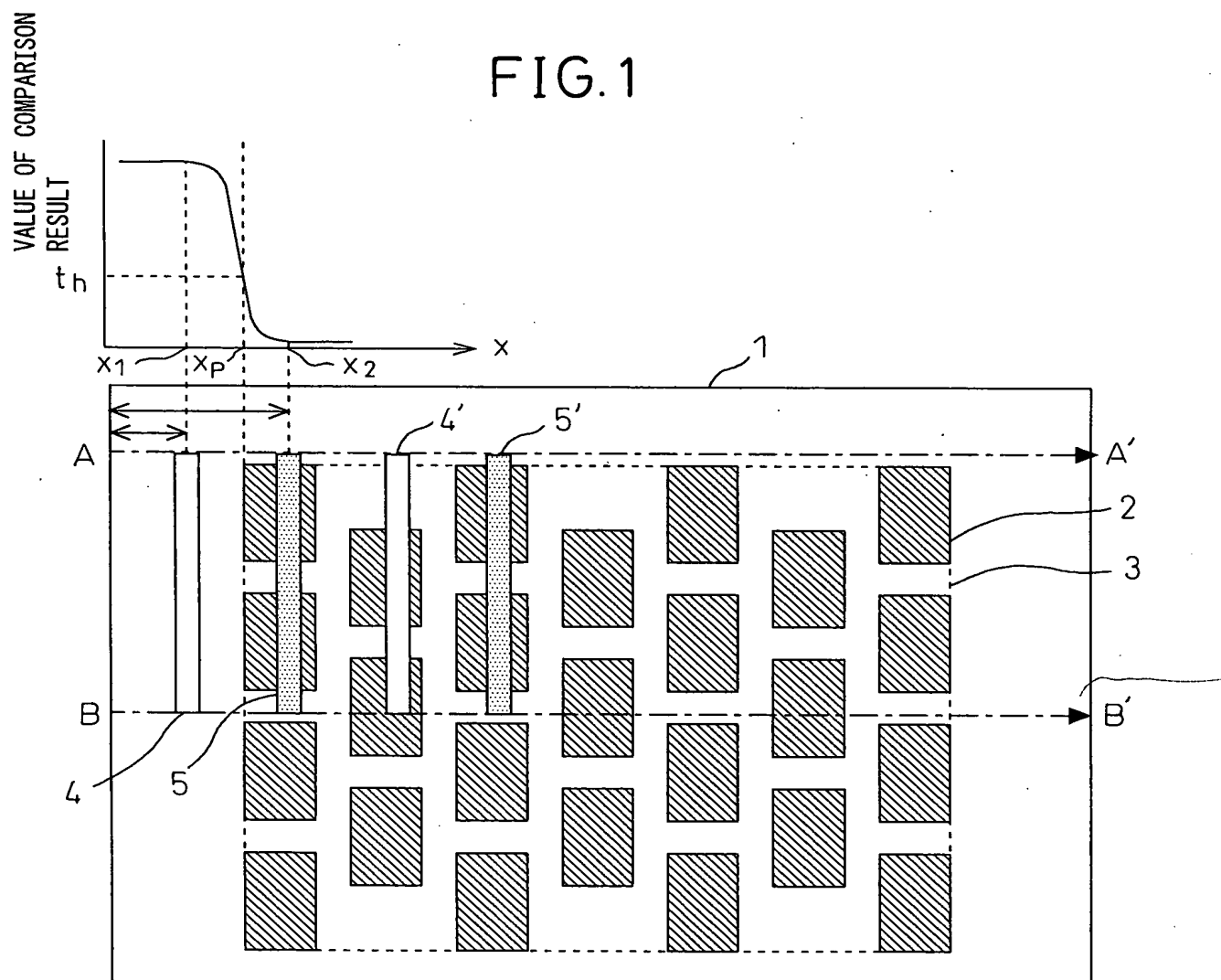


FIG. 2

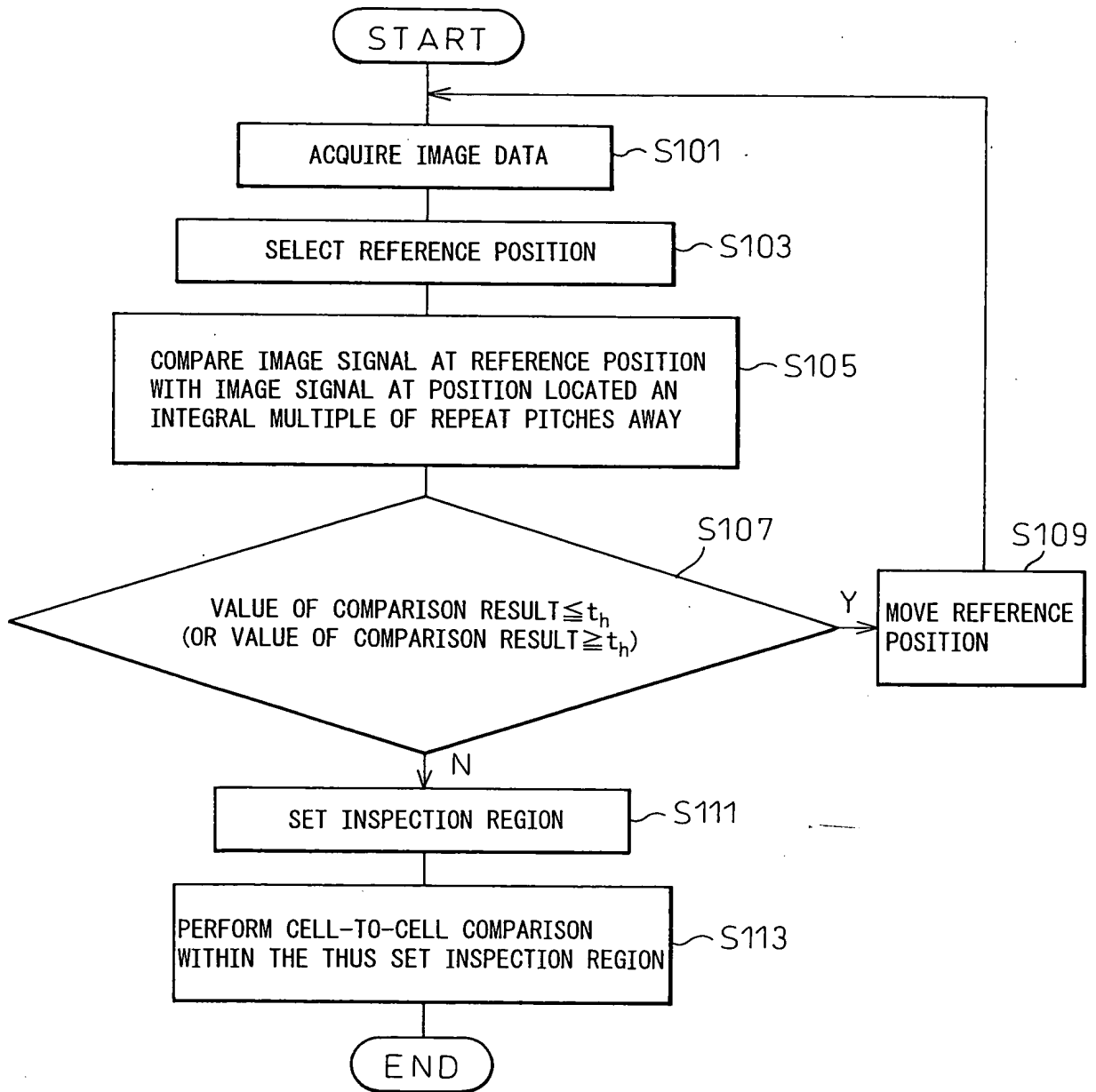


FIG. 3

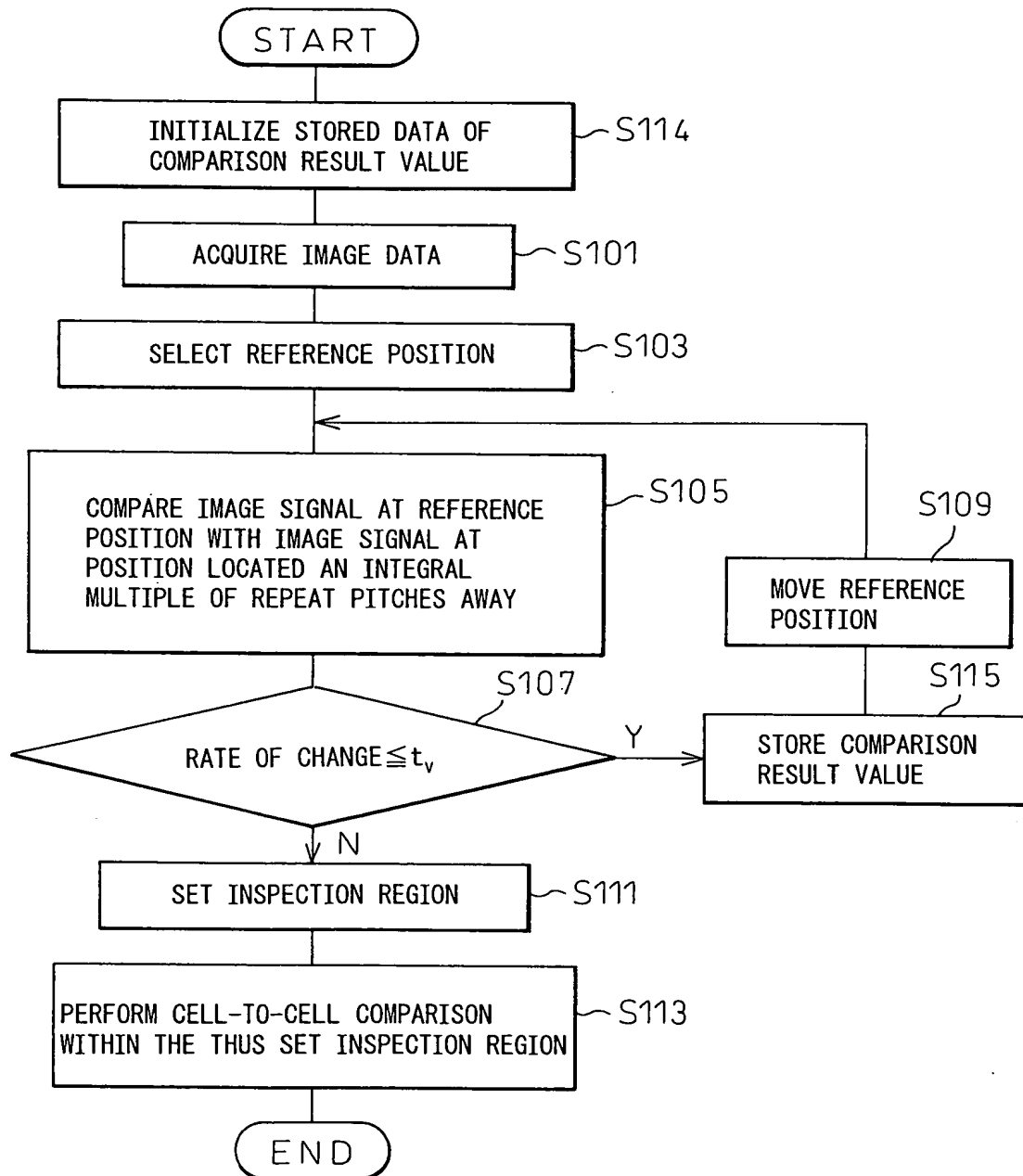


FIG. 4

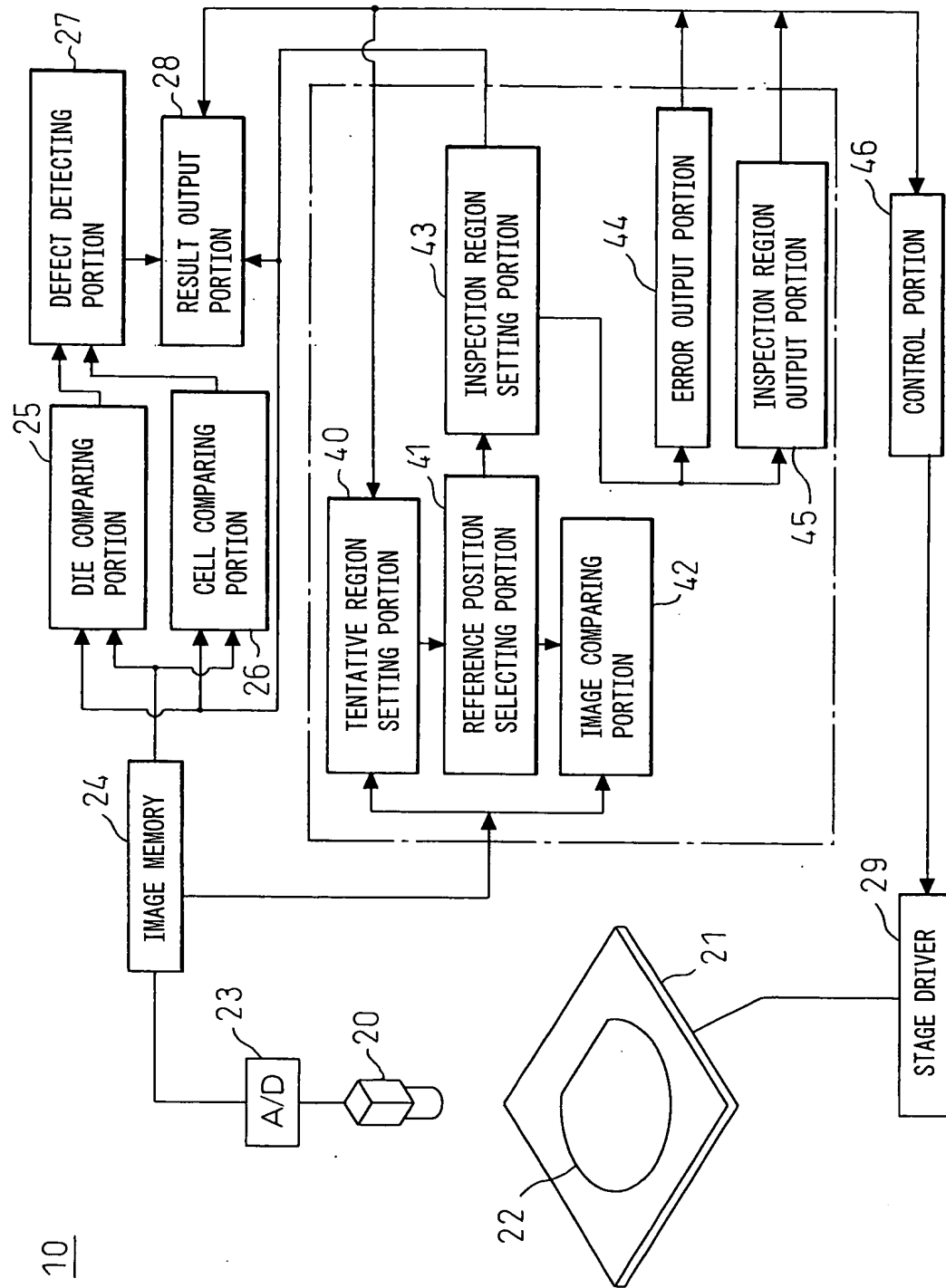


FIG. 5

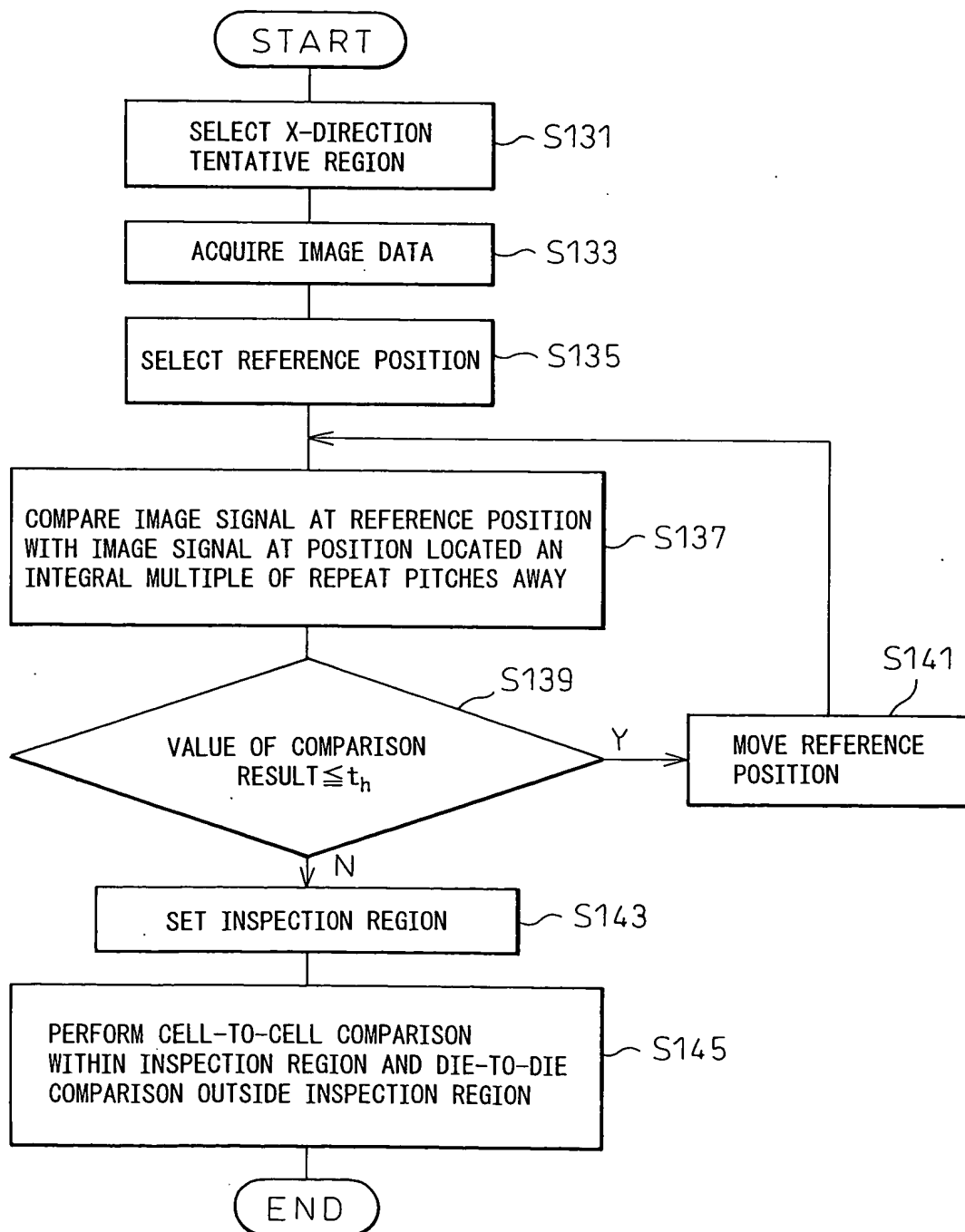


FIG. 6

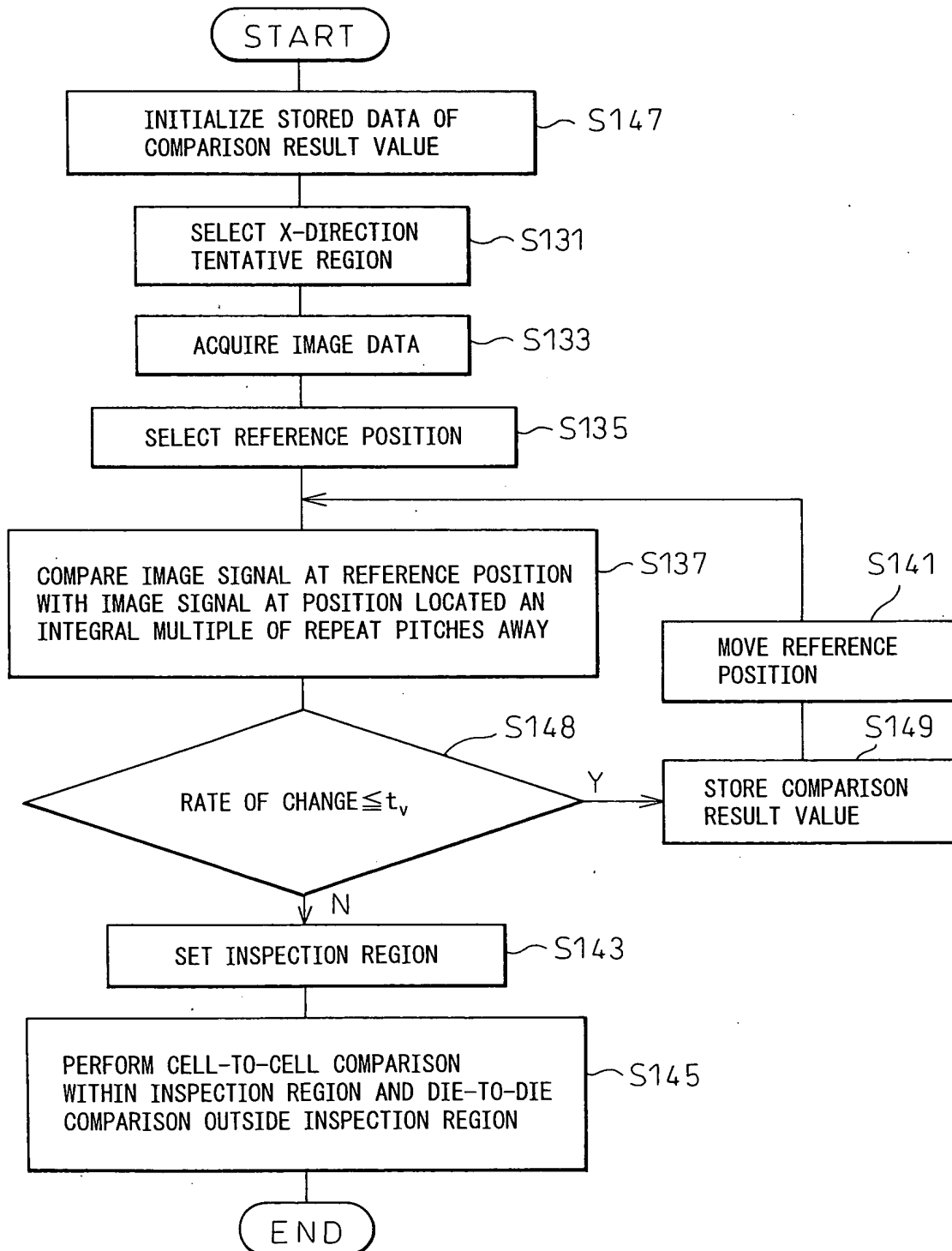


FIG. 7

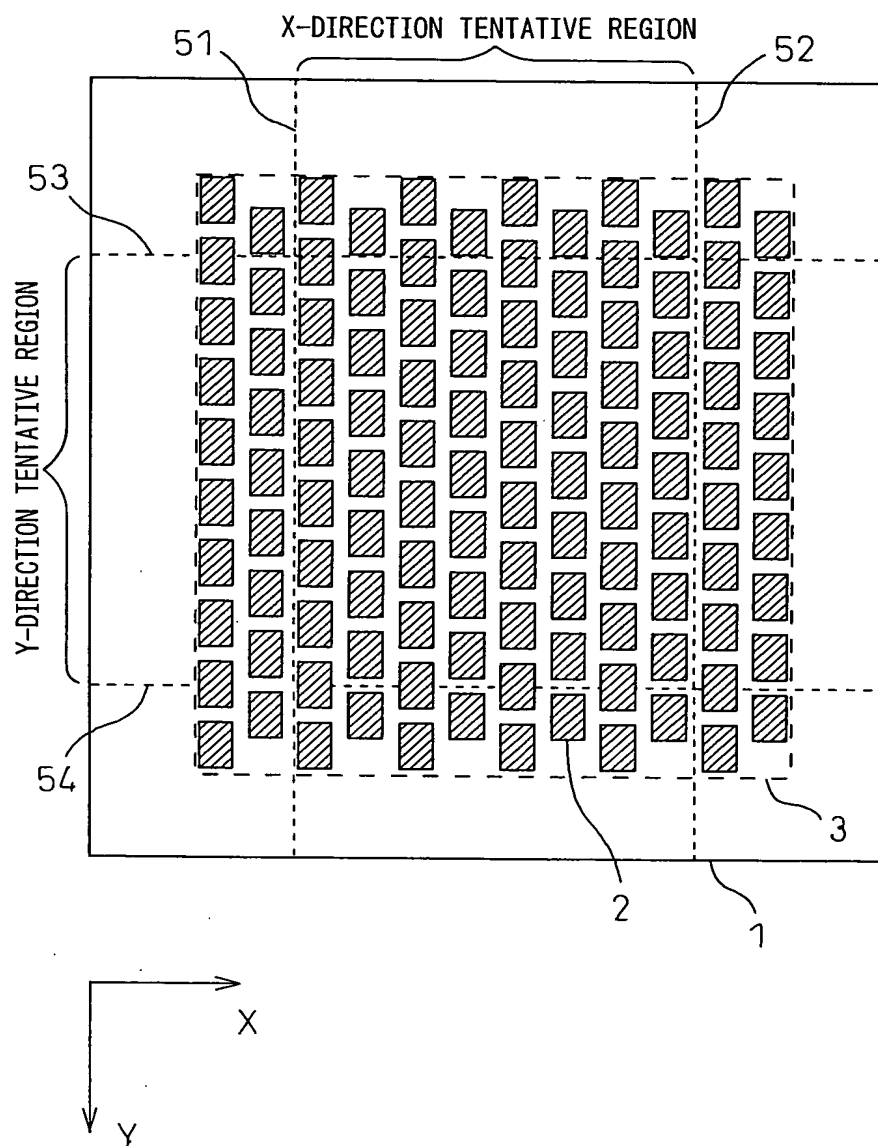


FIG. 8

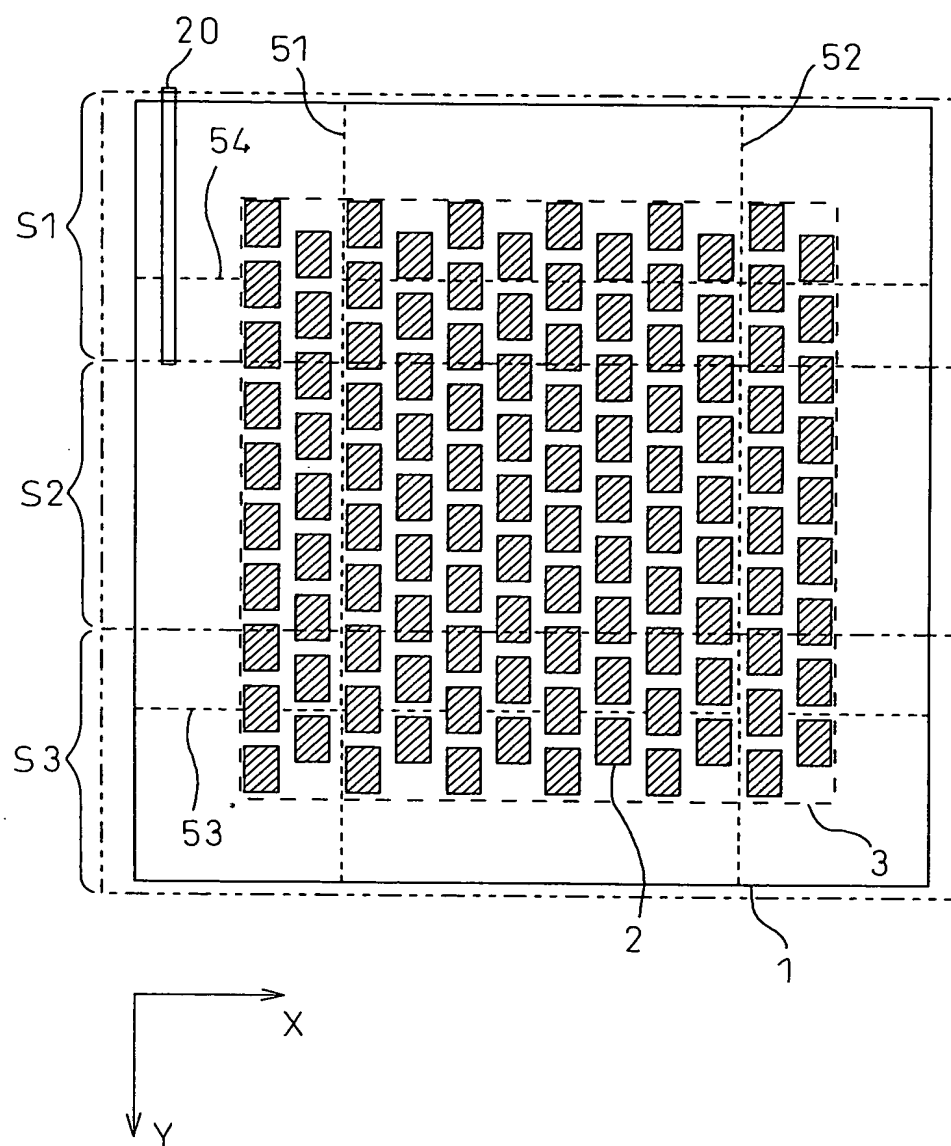


FIG. 9A

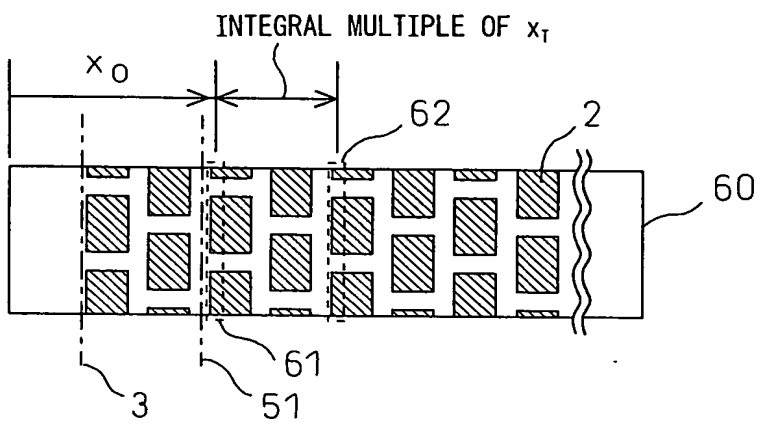


FIG. 9B

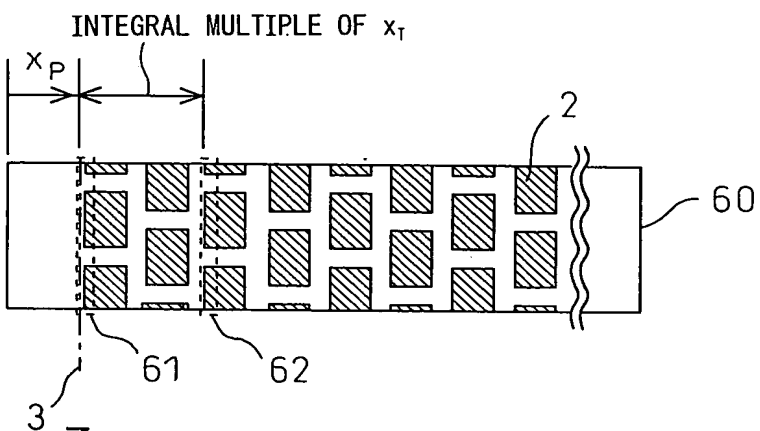


FIG. 9C

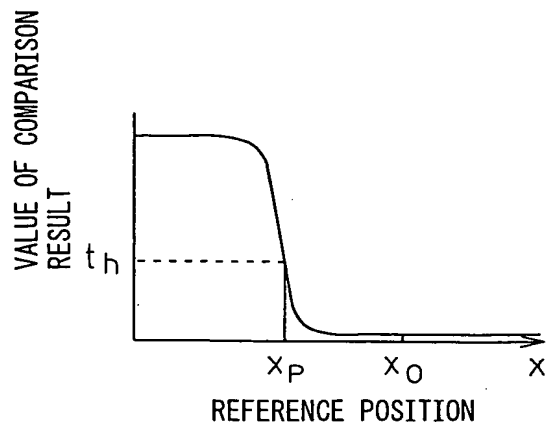


FIG. 10A

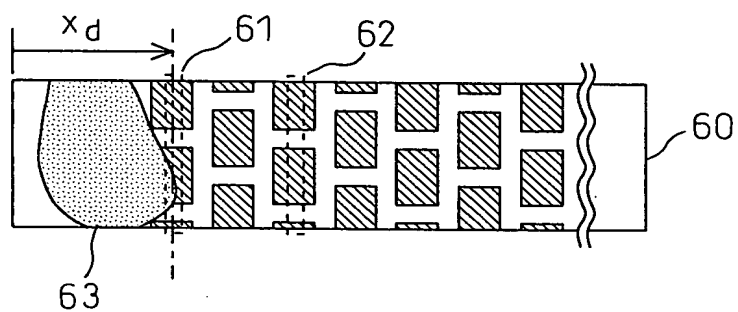


FIG. 10B

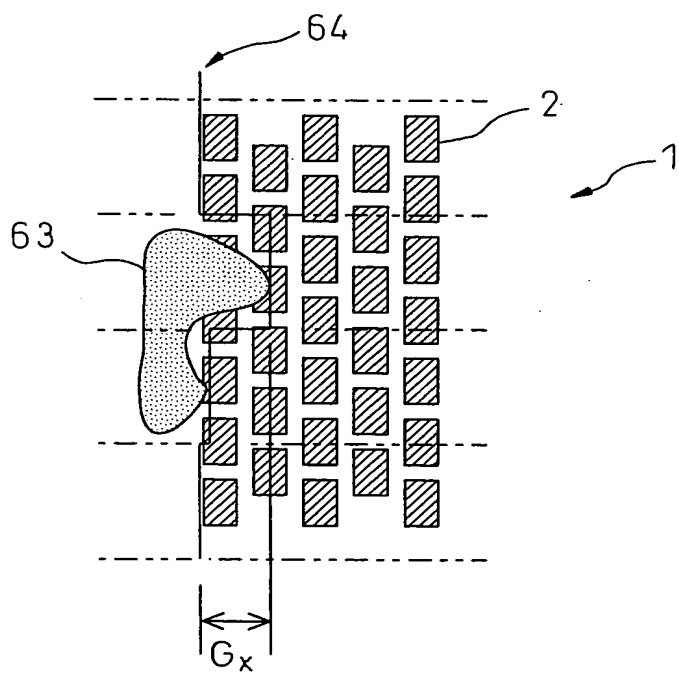


FIG.11

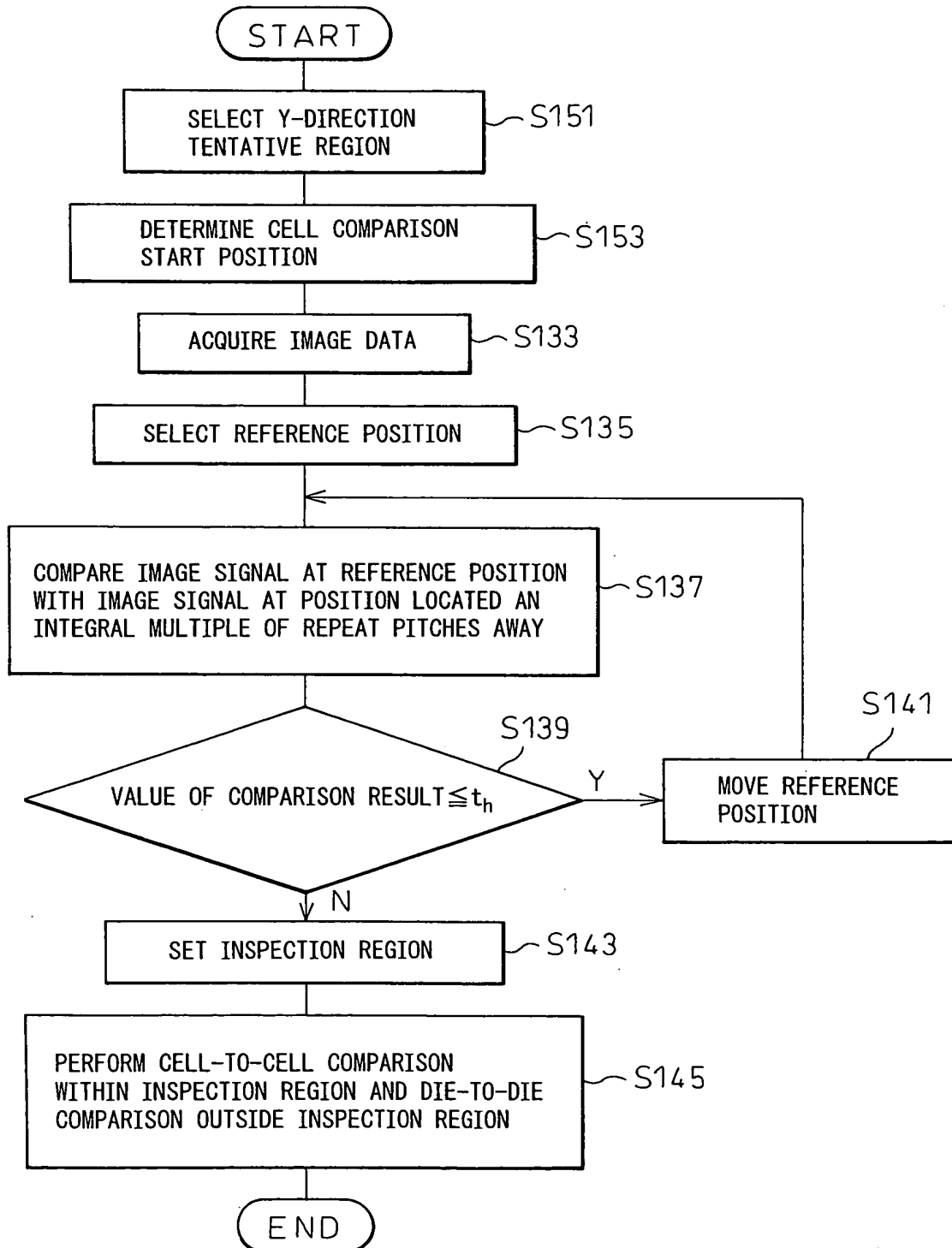


FIG.12

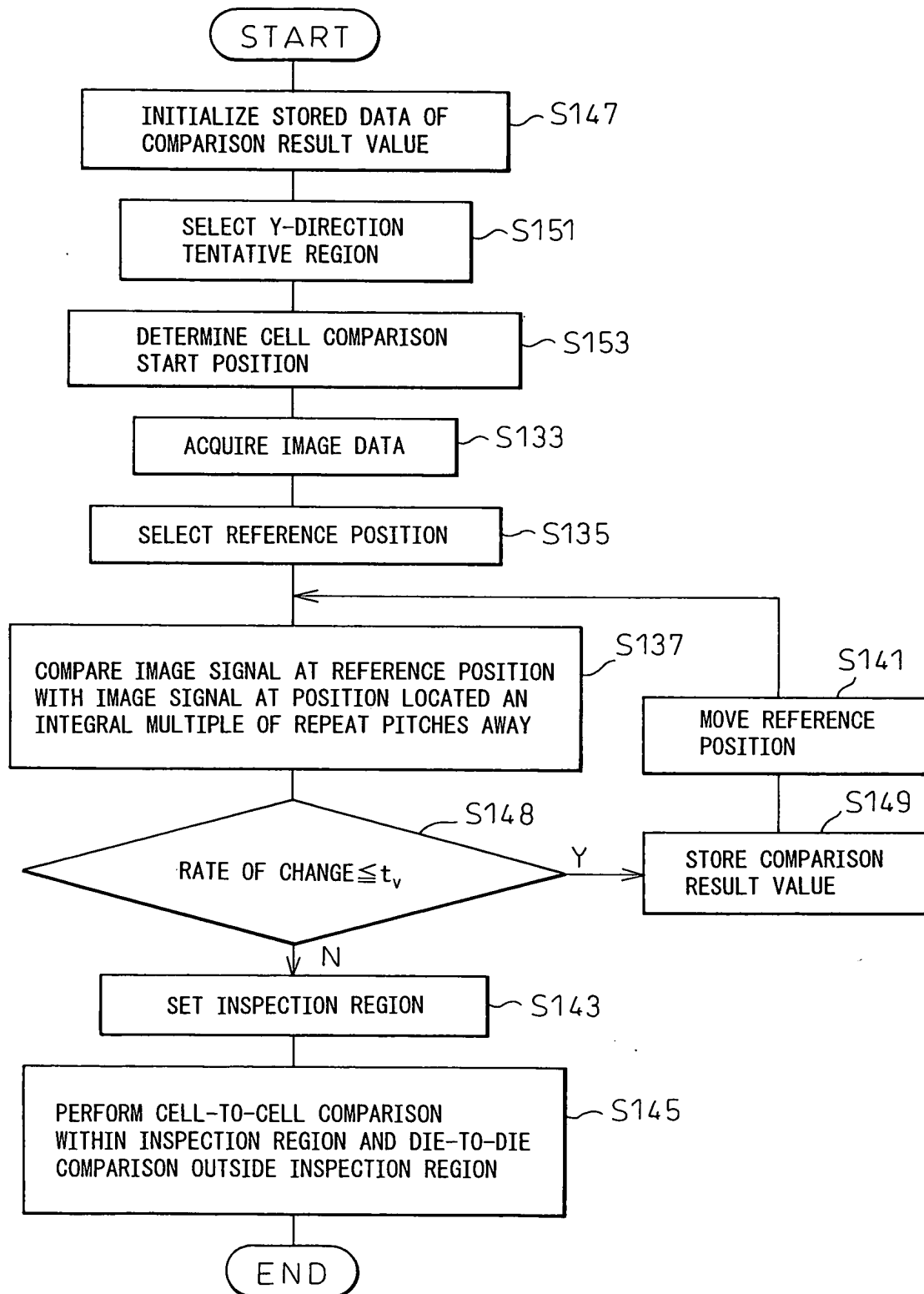


FIG. 13A

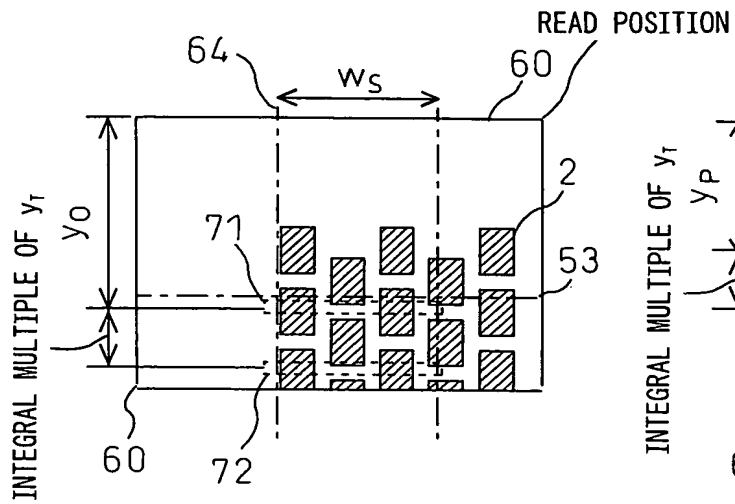


FIG. 13B

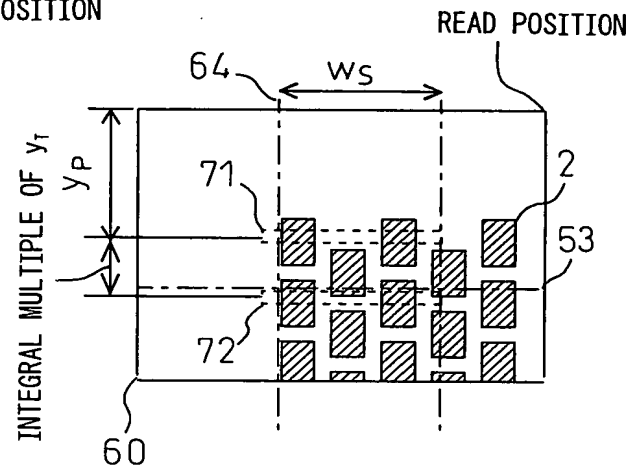


FIG. 13C

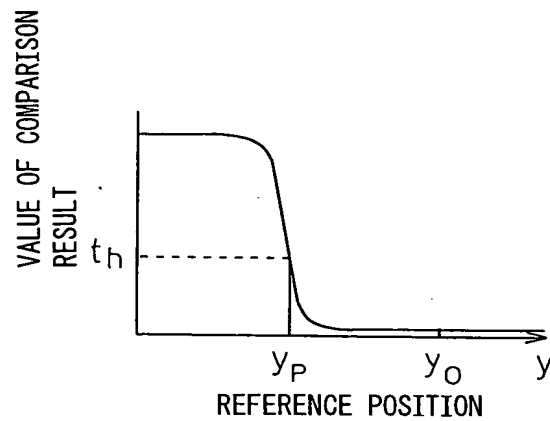


FIG. 13D

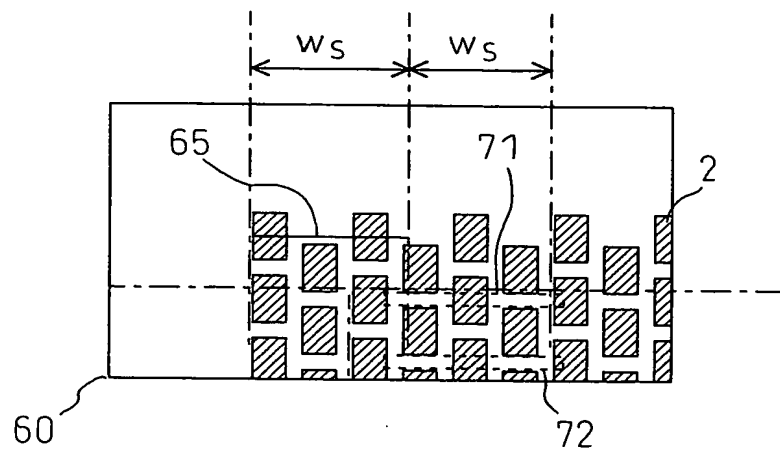


FIG.14

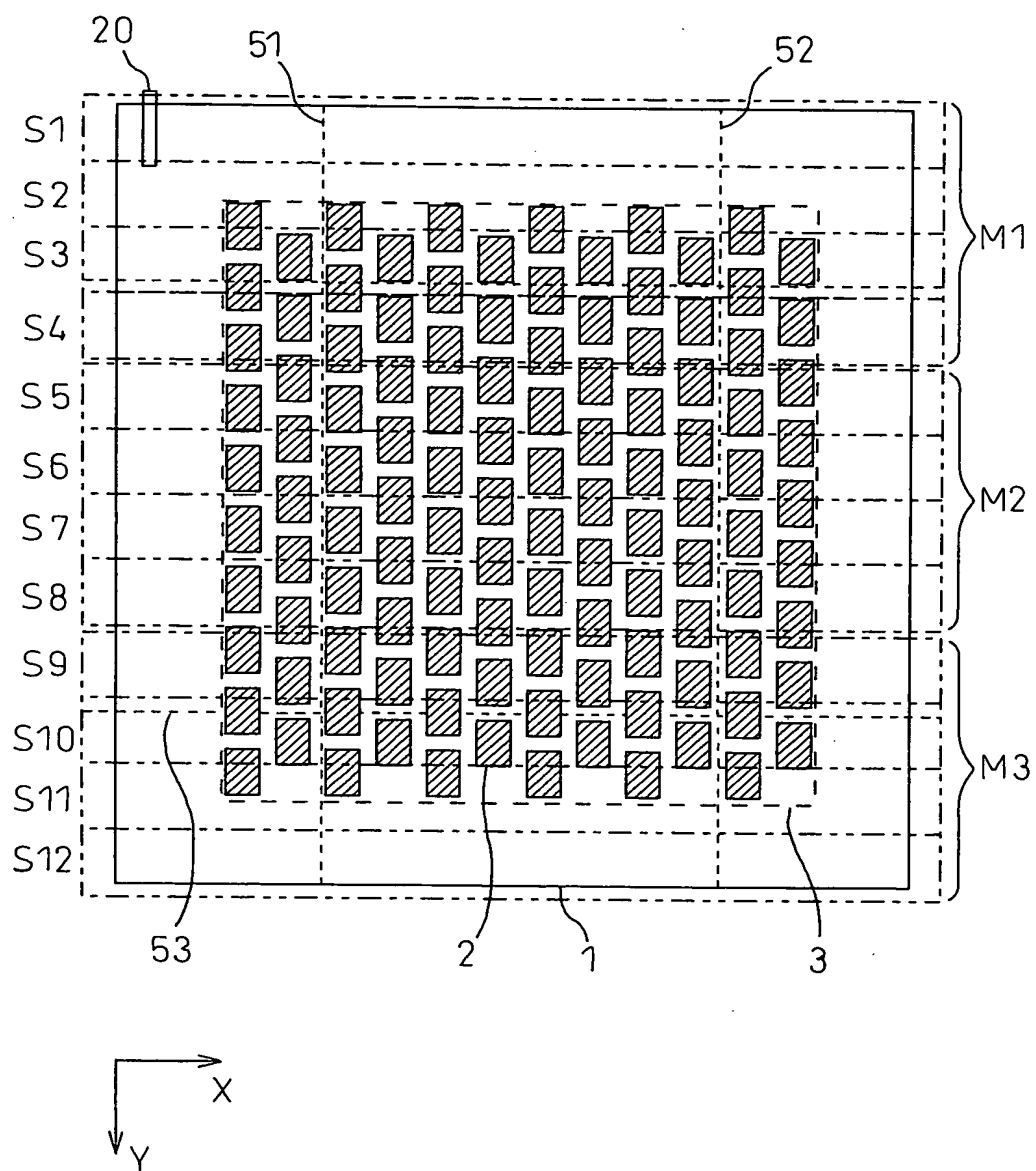


FIG.15

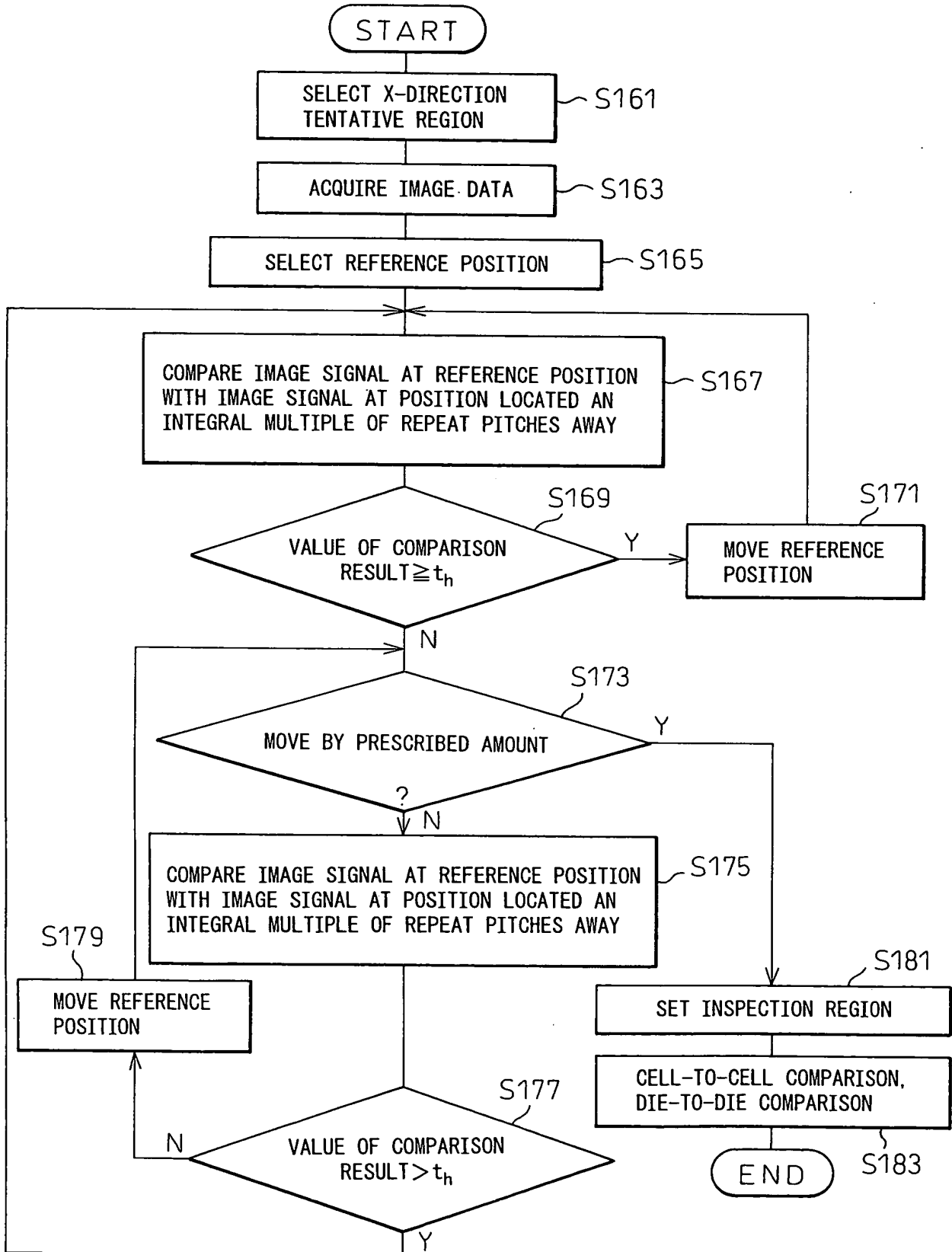


FIG.16

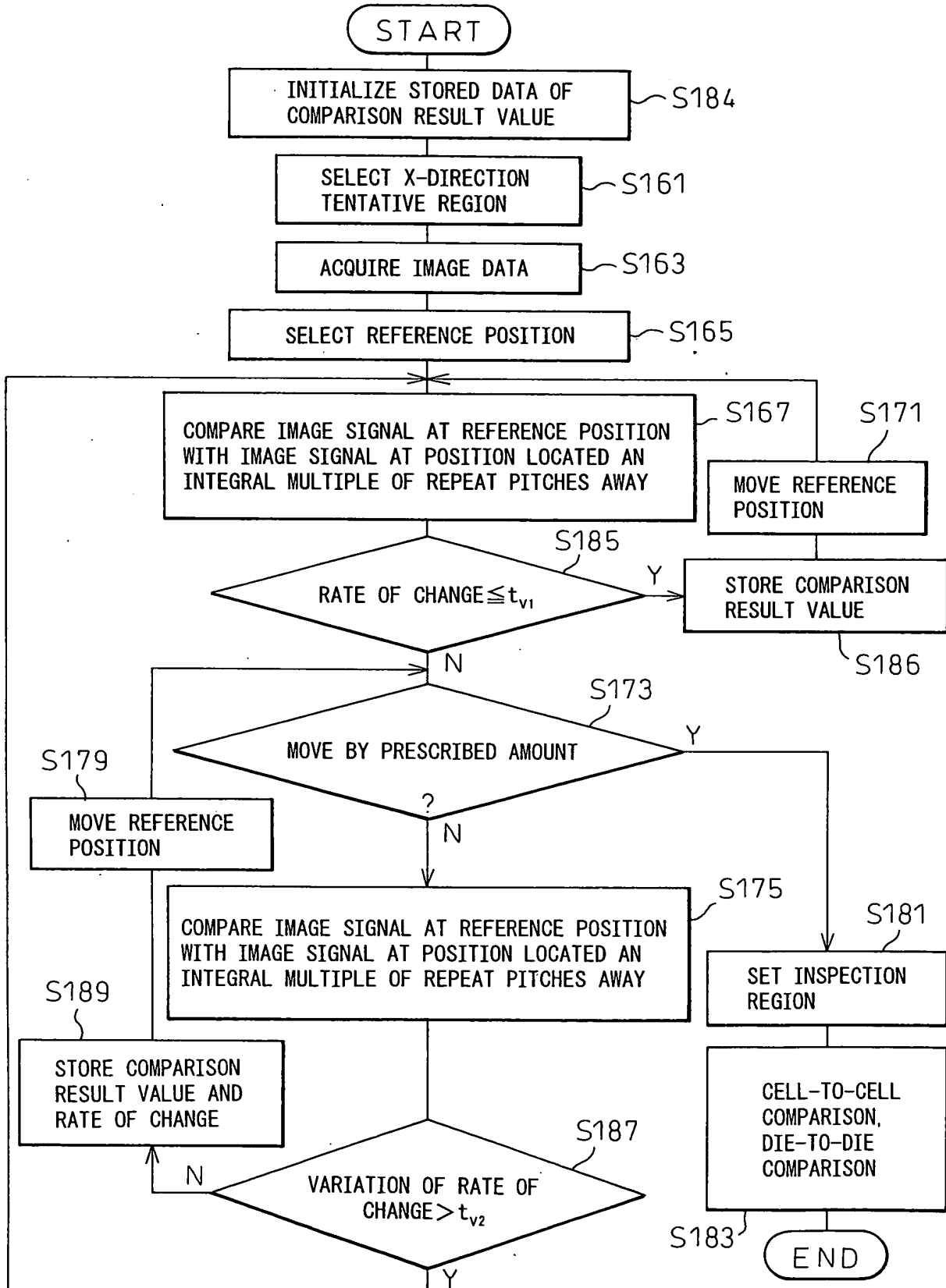


FIG.17

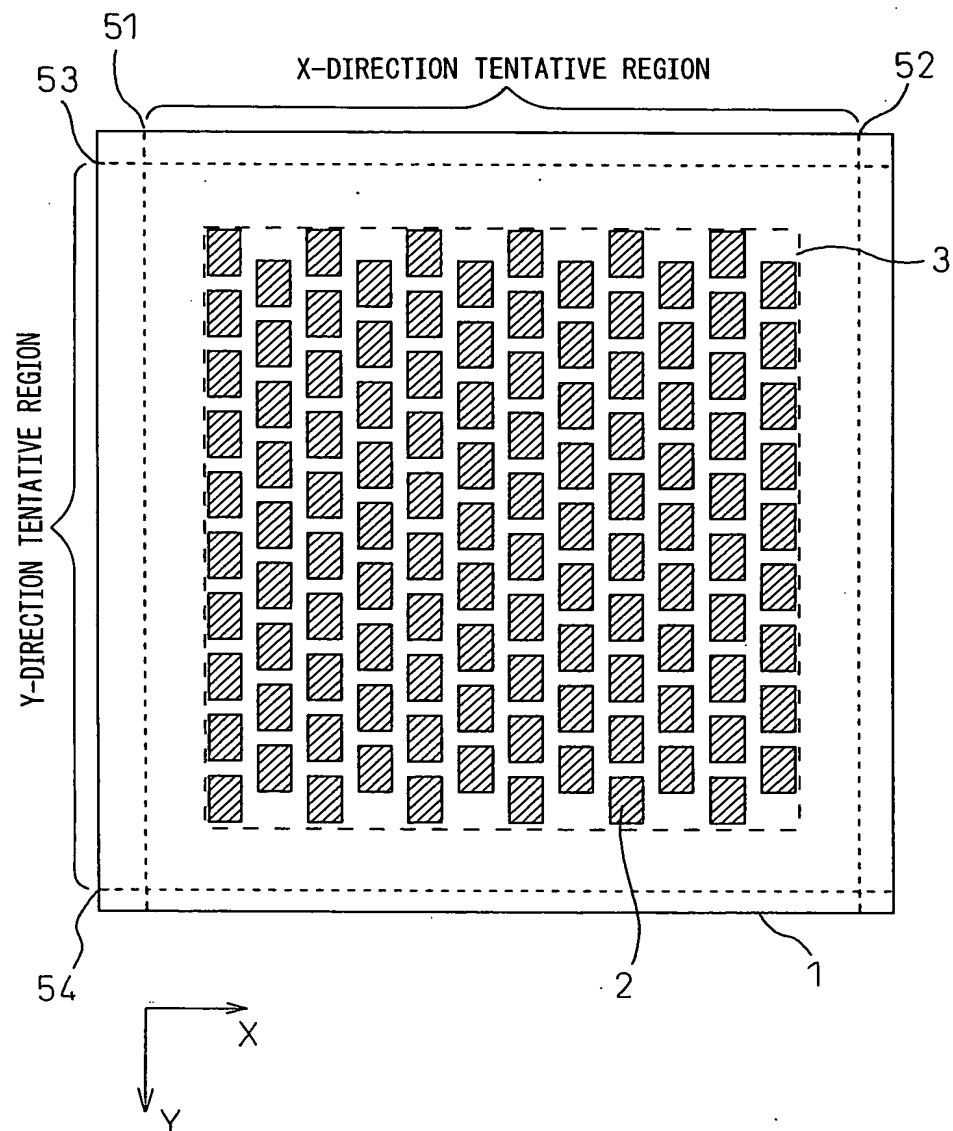


FIG.18A

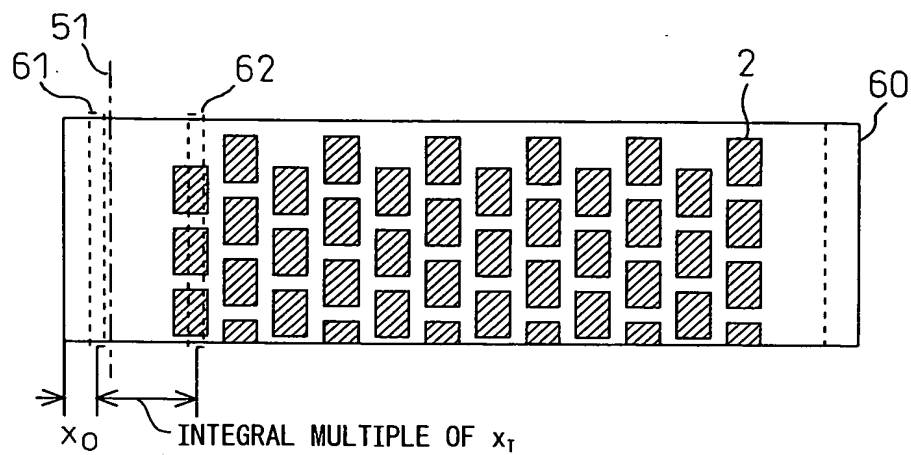


FIG.18B

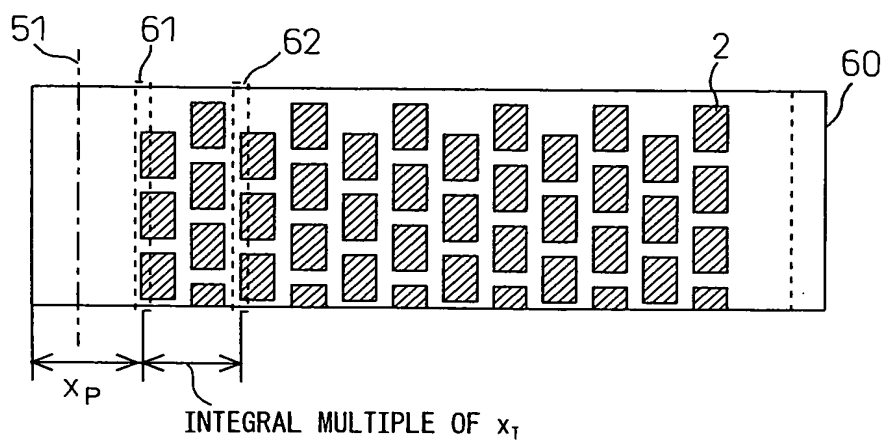


FIG.18C

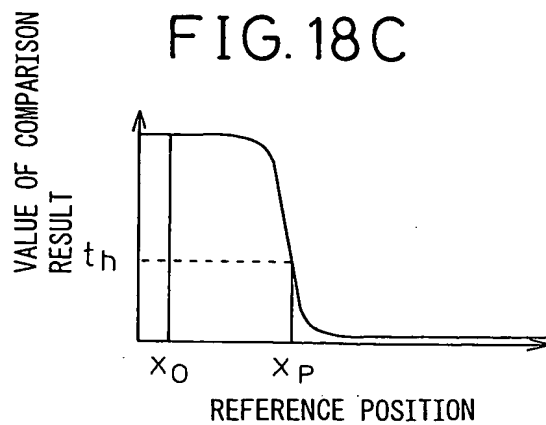


FIG.19A

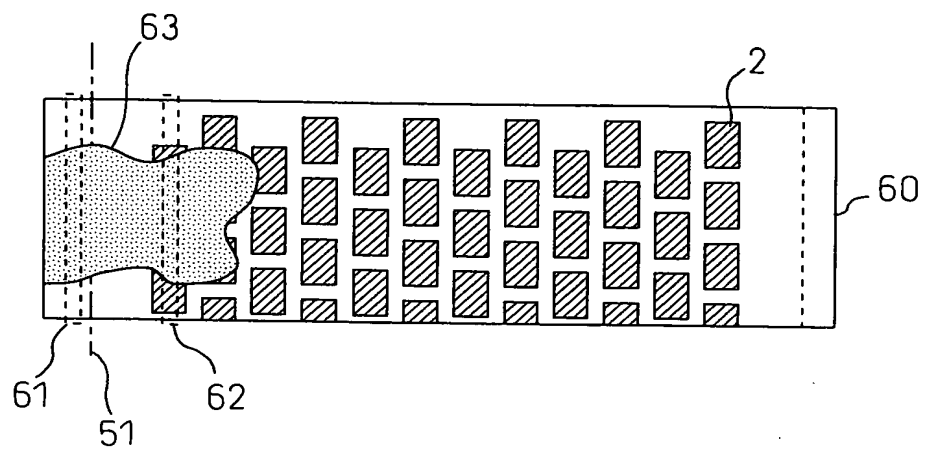


FIG.19B

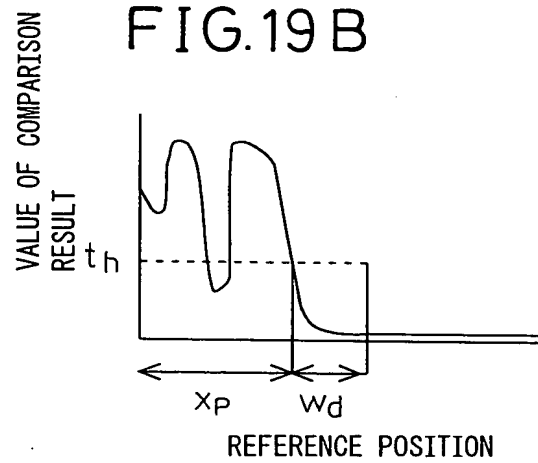


FIG. 20

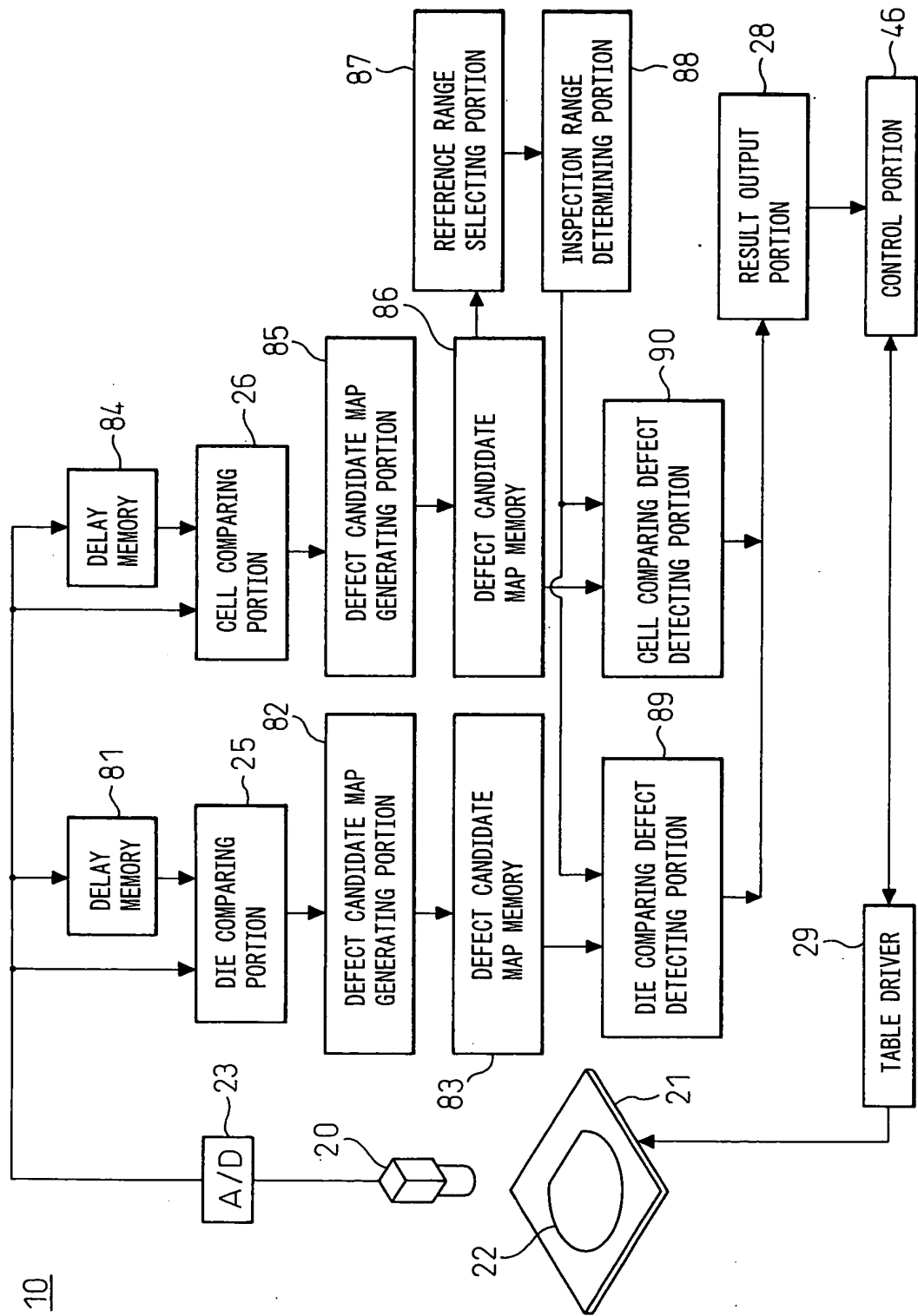


FIG. 21

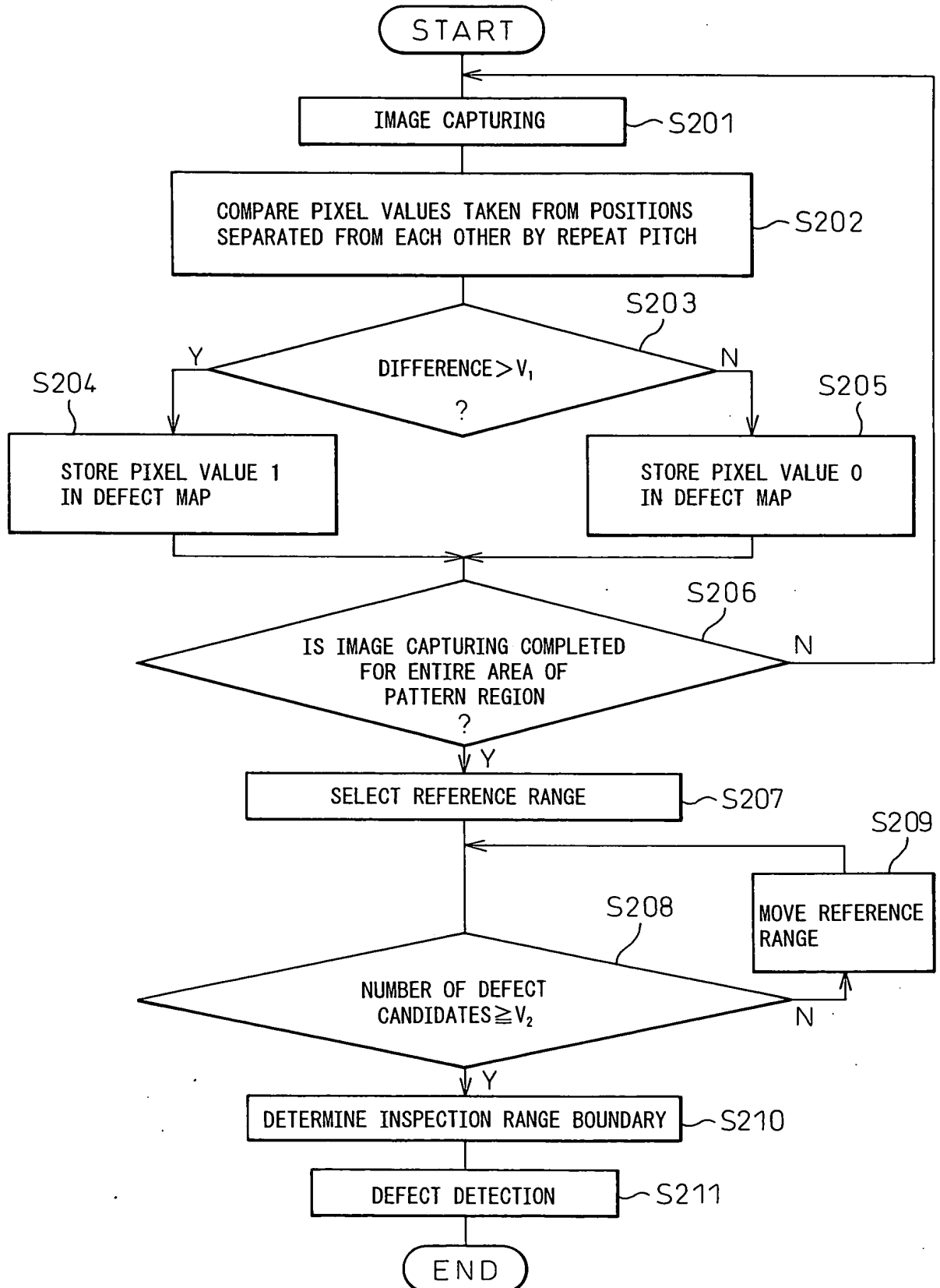


FIG.22A

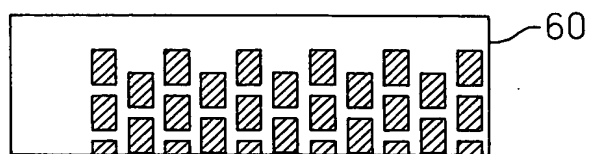


FIG.22B

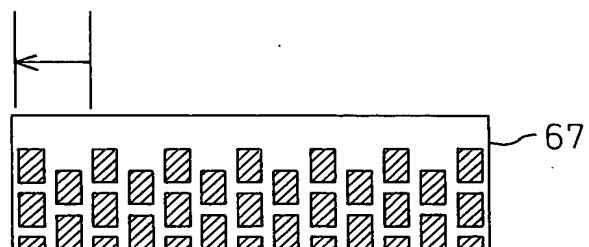


FIG.22C

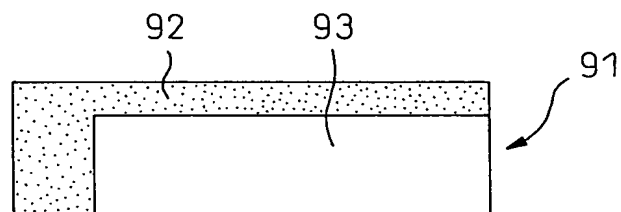


FIG.22D

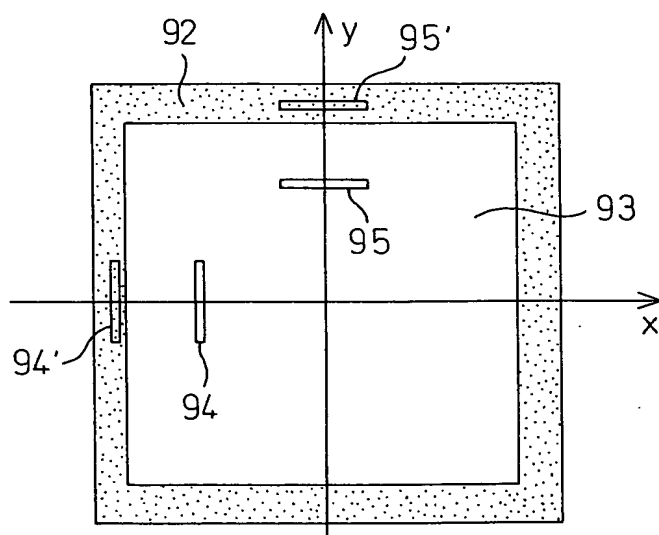


FIG.23A

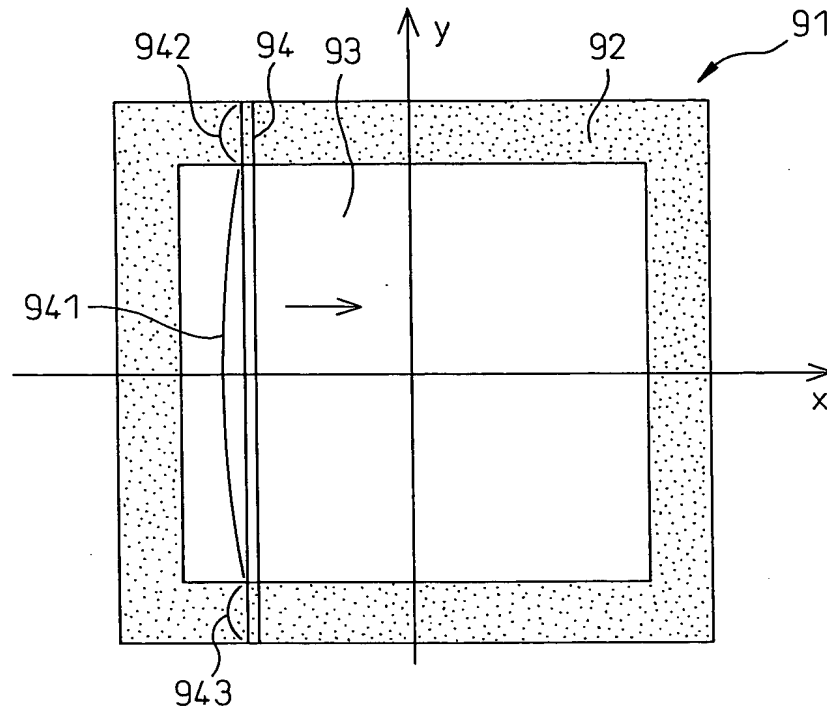


FIG.23B

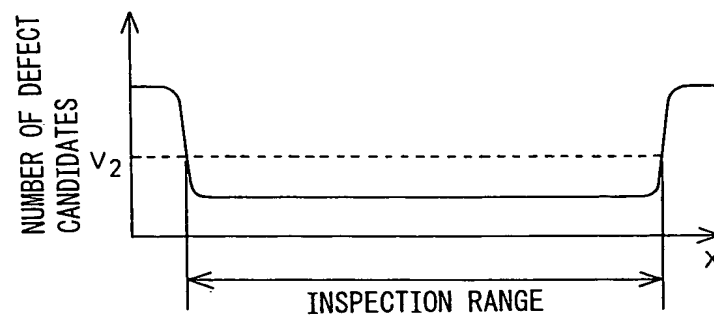


FIG.24

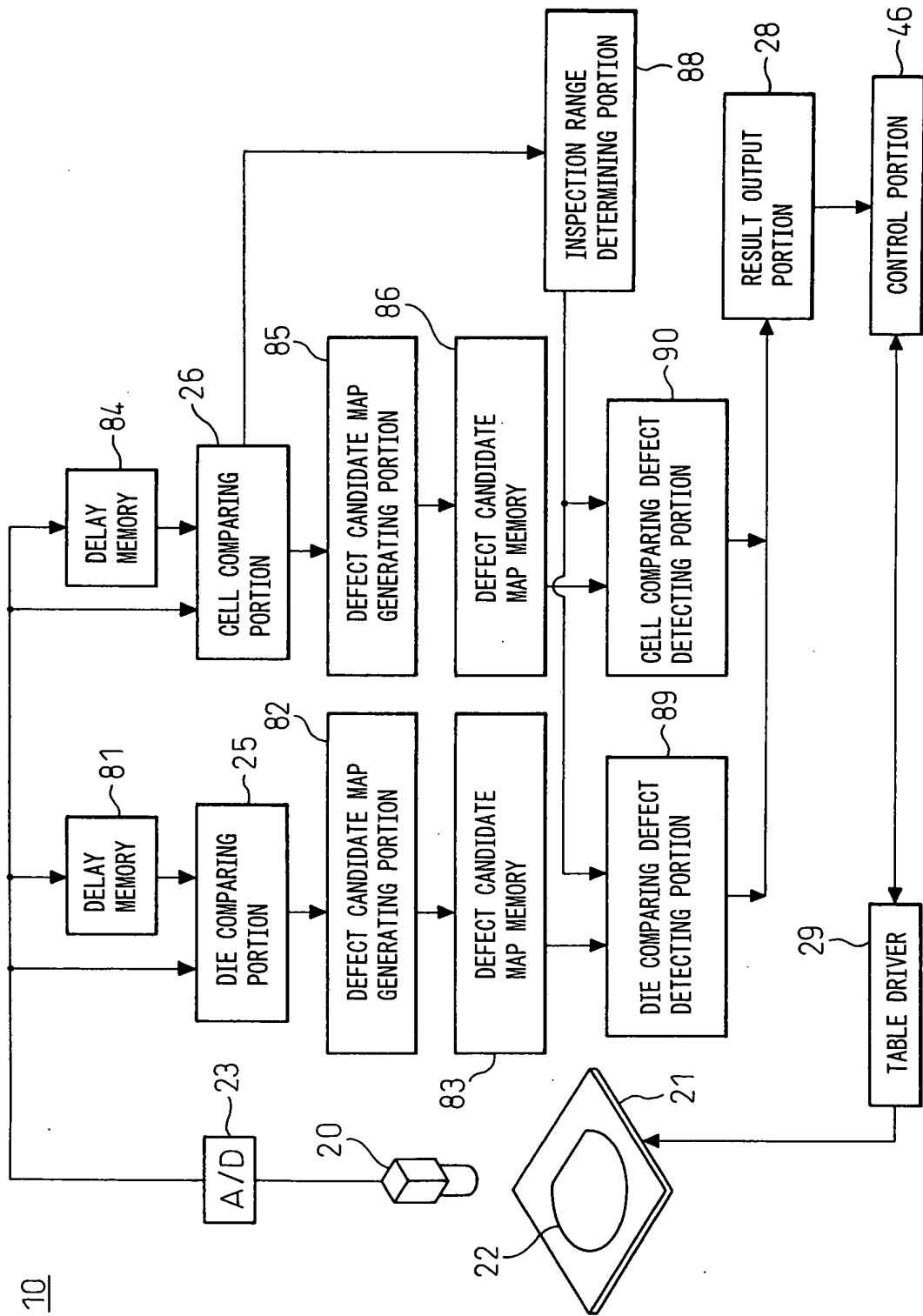


FIG.25

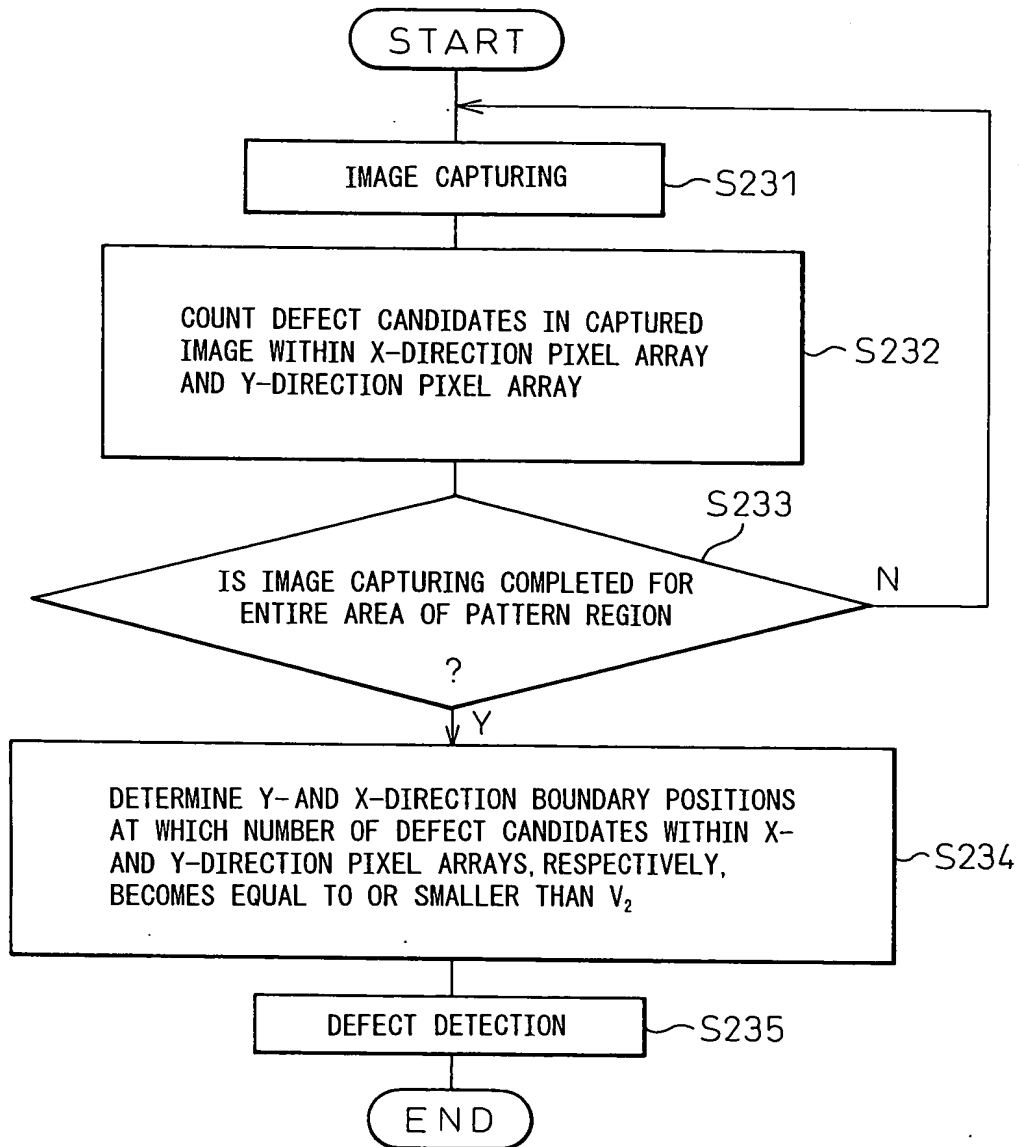


FIG.26

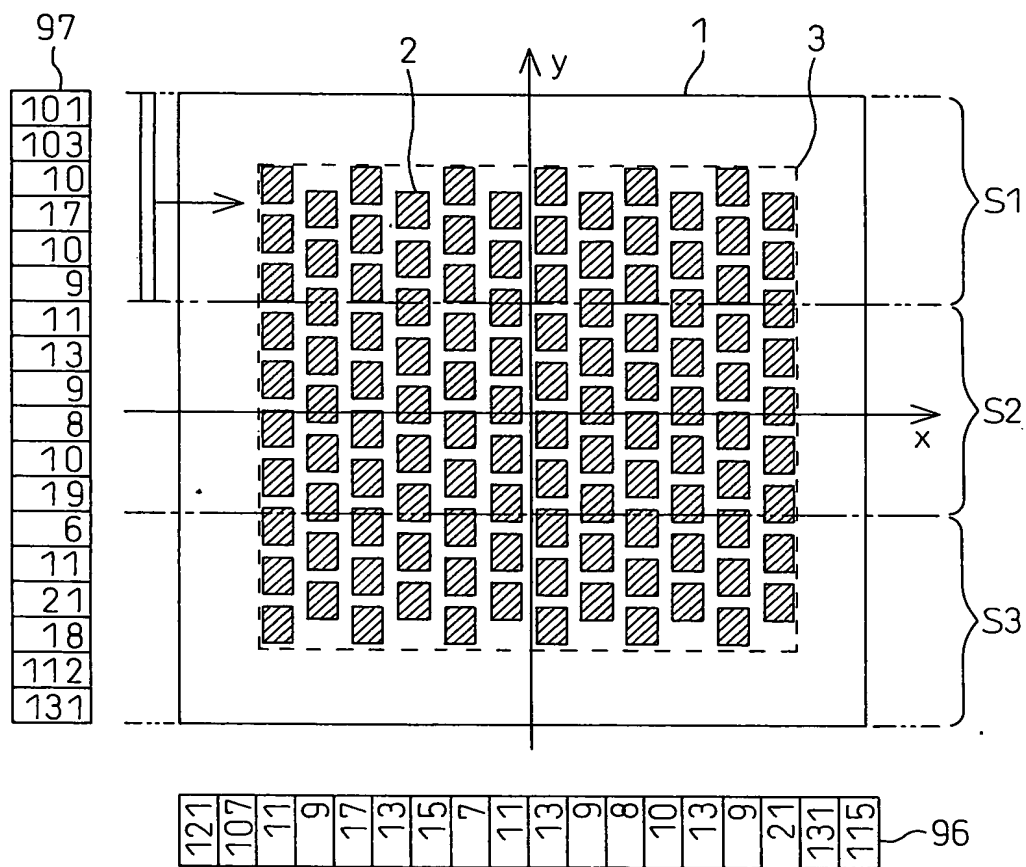


FIG. 27

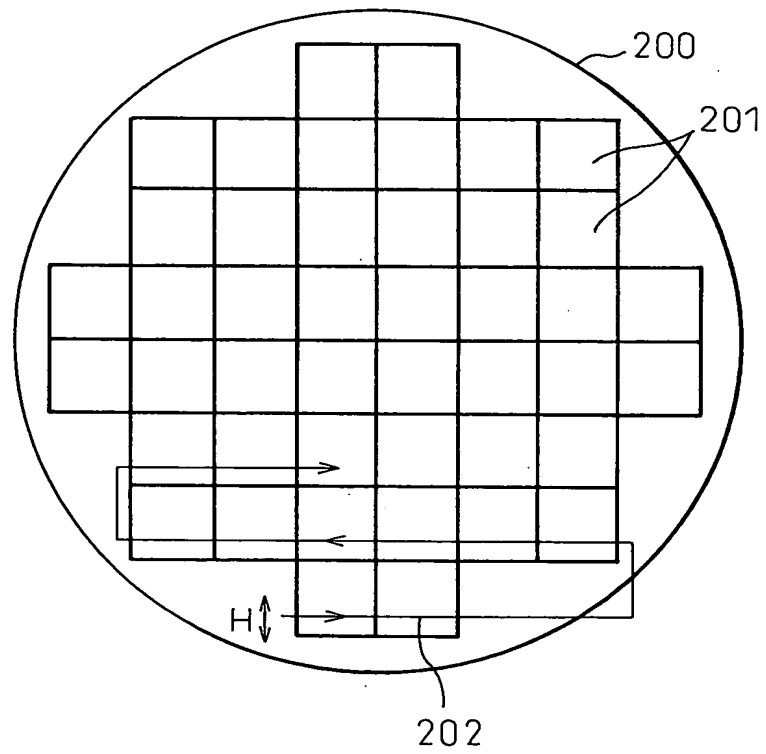


FIG. 28

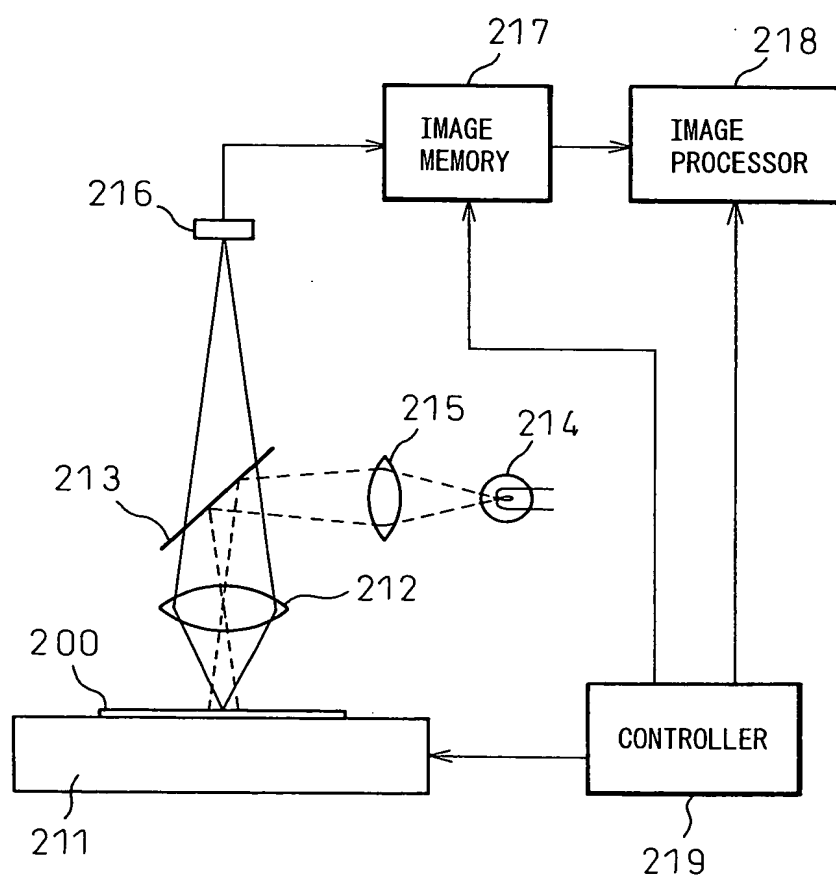


FIG. 29

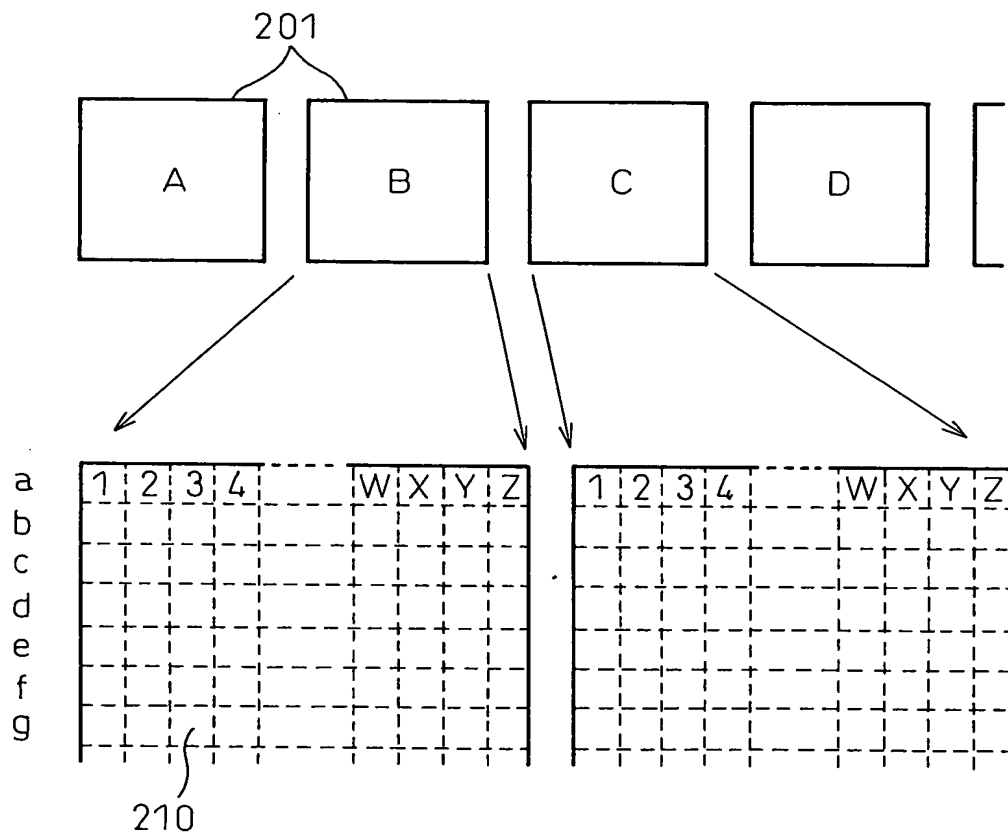
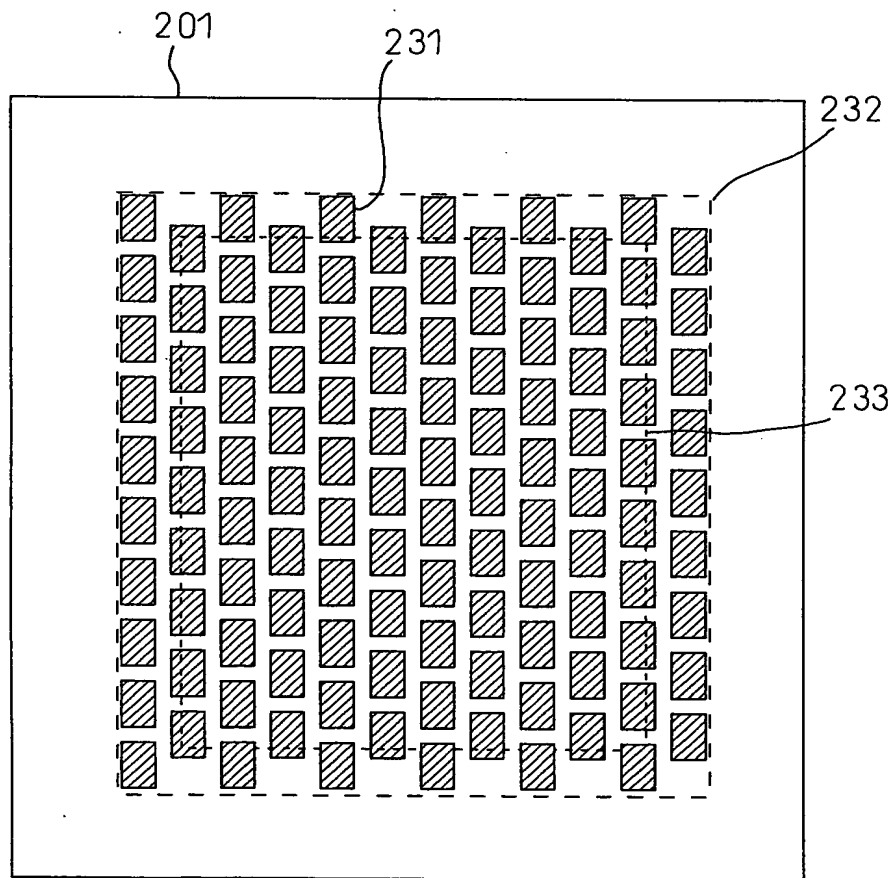


FIG. 30



DESCRIPTION OF THE REFERENCE NUMERALS

- 1 ... DIE
- 2 ... REPEATED PATTERN (CELL)
- 3 ... REPEATED PATTERN REGION
- 4, 5 ... PIXEL BLOCK
- 20 ... IMAGING PORTION
- 21 ... STAGE
- 22 ... WAFER
- 23 ... A/D CONVERTER
- 24 ... IMAGE MEMORY
- 25 ... DIE COMPARING PORTION
- 26 ... CELL COMPARING PORTION
- 27 ... DEFECT DETECTING PORTION
- 28 ... RESULT OUTPUT PORTION
- 29 ... STAGE DRIVER
- 40 ... TENTATIVE REGION SETTING PORTION
- 41 ... REFERENCE POSITION SELECTING PORTION
- 42 ... IMAGE COMPARING PORTION
- 43 ... INSPECTION REGION SETTING PORTION
- 44 ... ERROR OUTPUT PORTION
- 45 ... INSPECTION REGION OUTPUT PORTION